

ReticleSense™ Airborne Particle Sensor Quartz (APSRQ)

APSRQ

○ Improve equipment set-up and long term yields by wirelessly monitoring airborne particles in real-time.

Quickly monitors, identifies and enables troubleshooting of airborne particles down to 0.15um within semiconductor process equipment and automated material handling systems.

○ Ideal for use in FAB scanners and steppers that read barcodes and alignment in transmission.

Speed equipment qualification with wireless measurements.

- Collect and display particle data wirelessly using the APSRQ and Particle View™ software for real-time equipment diagnostics.
- Compare past to present as well as one tool to another with recorded particle data.
- Save time by swiftly locating contamination sources with the APSRQ data and see the effect of cleanings, adjustments and repairs in real time.

Shorten equipment maintenance cycles with reticle-like form factor.

- Detect particles in real-time without opening the tool so you don't need to expose process areas to the environment.
- APSRQ goes where reticles go to find the place where particles contaminate reticles.
- Once the location of particles is identified, tools may be selectively cleaned. Open only the dirty portion, keep the clean areas clean.

Lower equipment expenses with objective and reproducible data.

- Raise your first-pass monitor reticle success, reduce your qualification expense and increase availability with APSRQ.
- Receive early warning for impending equipment failures and optimize your preventative maintenance plans.
- Establish a baseline from known clean tool, then cycle APSRQ through a candidate tool before committing monitor reticles.

Semiconductor fabs and OEMs worldwide value the accuracy, precision and versatility of the ReticleSense APSRQ – The most efficient and effective wireless measurement device for airborne particles.



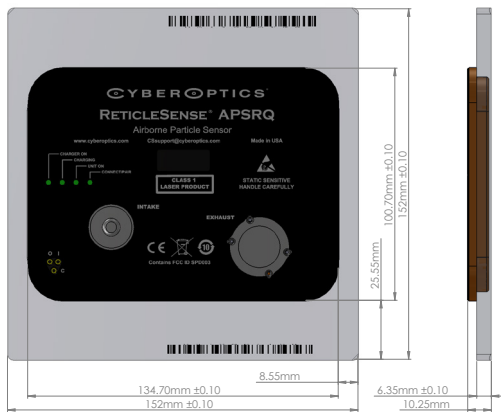
Save Time. Save Expense. Improve Yields.

Features*

Wireless, reticle-shaped and battery-powered	Available in 6 inch Reticle form factor
Easy-to-use software	ParticleView and ParticleReview software included ParticleView: Displays real-time numeric and visual feedback, cumulative or differential counting modes and density or frequency modes ParticleReview: Replays log file data for review and analysis
Highly accurate	Measures particles greater than 0.15um Size channels: Reports particles in 0.1um and 0.5um bin sizes
Durable housing	Quartz outer frame: Rear surface of quartz frame is an uninterrupted quartz surface
Barcodes and Alignment	Bar codes and alignment marks allow placement in most scanners and steppers
Airflow	0.07CFM (2L/m) @ 1 atmosphere
Operating pressure	0.4 to 1.6 atmosphere
Operating internal temperature	15 deg C to 45 deg C non-condensing
Battery-operation	>1 hour per charge
WaferSense Link	Bluetooth, 2.4 GHz, USB 1.1, dimensions 92mm x 58mm x 28mm
Operating Systems	Windows 7, XP and Vista
Product components	Particle measurement device, charging clean case, carrying suitcase, USB communications link module and application software
Calibration	Factory recalibration recommended annually

*Preliminary Specifications Subject to Change

Dimensions



ParticleView™



Real-time data.



Contact CyberOptics today for your complimentary on-tool demonstration
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